

SiPM Radiation results at $5E13$ n/cm² for CMS - Barrel Timing Layer

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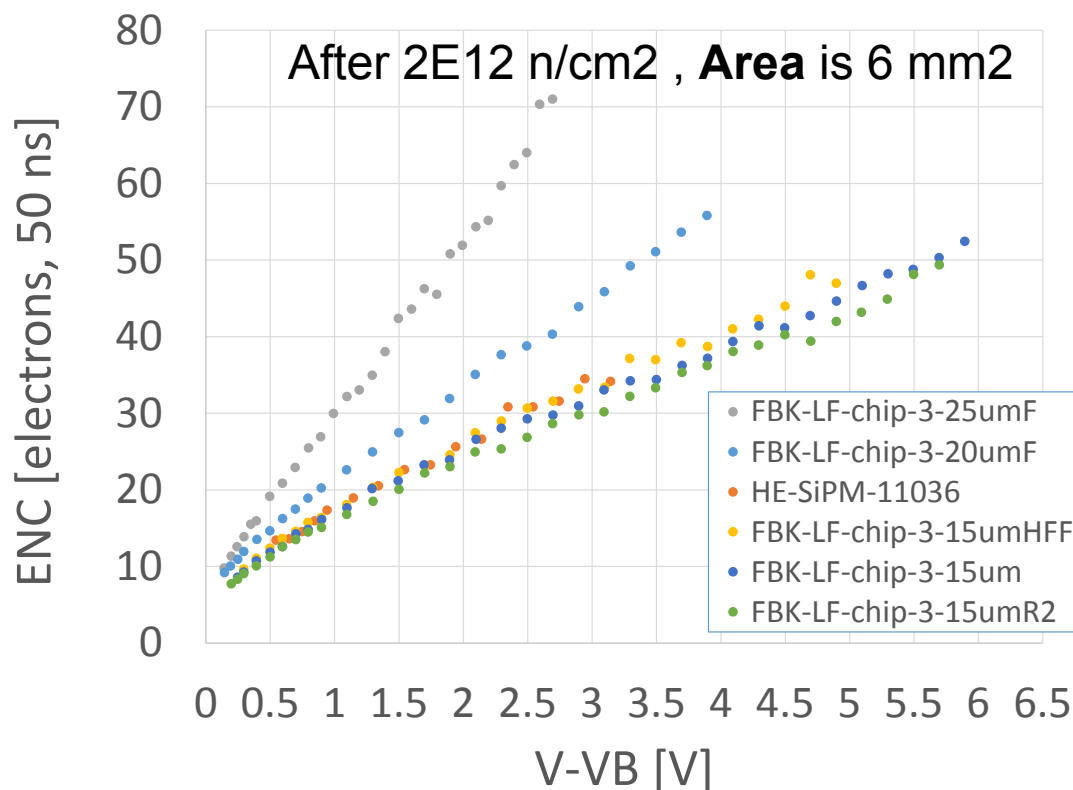
* On leave from INR(Moscow)

Samples were submitted in DEC 2016 returned and in MAR 2017

	2.00E+12 n/cm ²	5.00E+13 n/cm ²	Number of samples (2E12)	Number of samples (5E13)
FBK NUV	FBK-LF-chip-3	FBK-LF-chip-5	6	6
	FBK-SF-chip-6	FBK-SF-chip-8	6	6
	FBK-5um-1	FBK-5um-2	1	1
RGB UHD2	FBK-7.5um-1	FBK-7.5um-2	1	1
	FBK-10um-1	FBK-10um-2	1	1
	CMS-5706-3	CMS-5703-5	1	1
HPK catalog		HPK-S12571-010-C-406		1
		HPK-S12571-015-C-183		1
		HPK-S13360-1325CS-10326		1
HE HPK	NDL-2	NDL-4	1	1
	S10943-4732-11036	S10943-4732-11064	8	8
	KETEK-PP-array-39	KETEK-PP-array-40	4	6
	MAPD-3N-1	MAPD-3N-2	1	1
New HPK	HD-1015CN-SMPA_2	HD-1015CN-SMPA_3	1	1
	HD-1025CN-SMPA_5	HD-1025CN-SMPA_6	1	1
	CMS-5701-2	CMS-5706-4	1	1
			33	38
	HB	BH/BTL		

HE HPK = production SiPM developed for CMS HCAL ENDCAP

NUV FBK (23C, after annealing) vs HPK



March 2017 analyses using pulsed LED

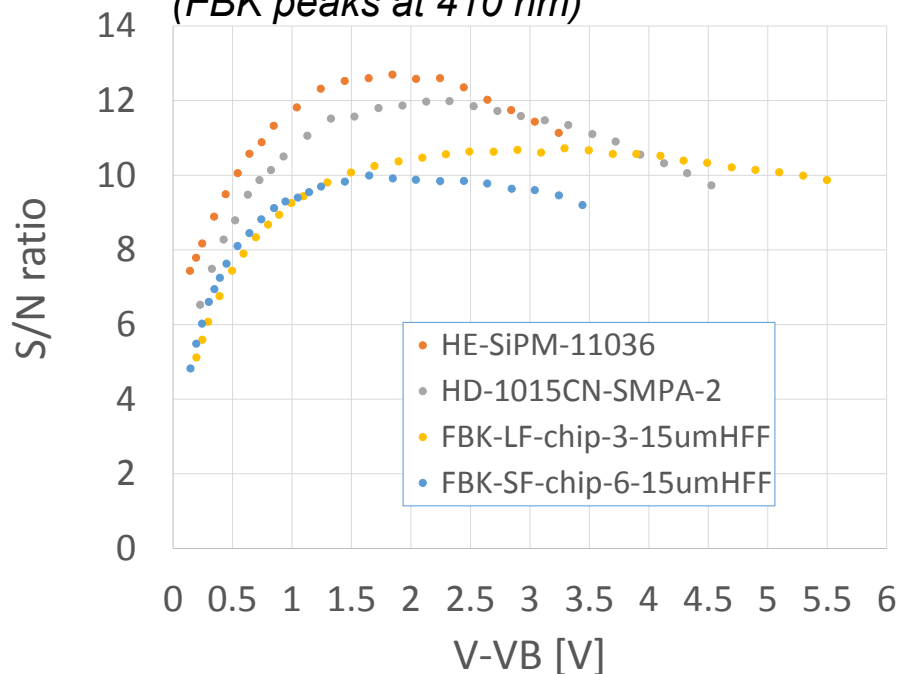
We found 25p.e. noise in 50 ns gate at 23C ; We estimated in GHz :

$25^2/50$ ns = 12.5 GHz

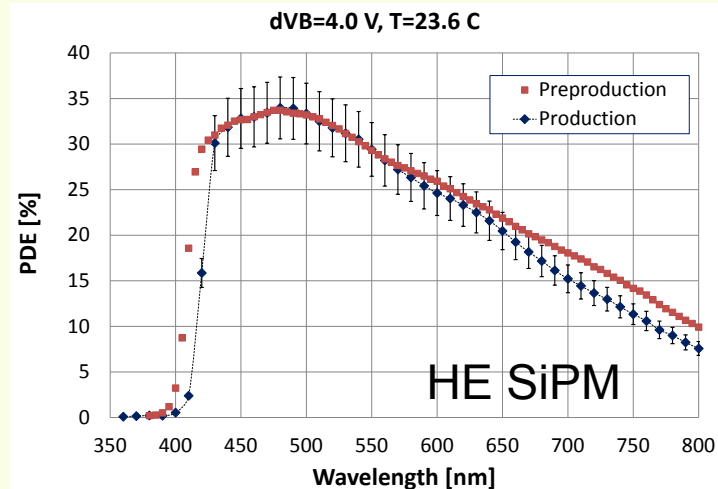
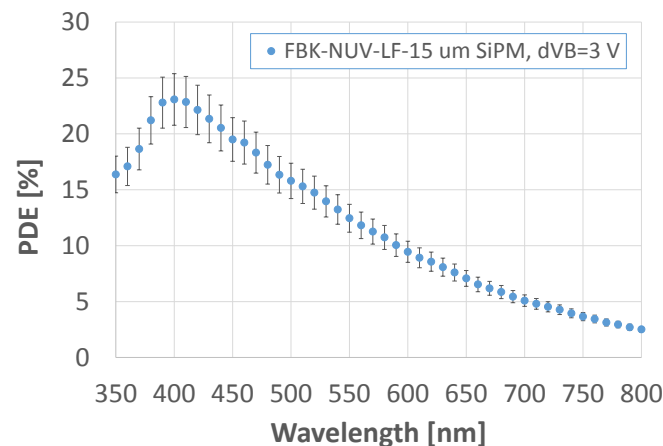
60 C lower temperature $\rightarrow 12.5 / (1.8)^6 = 0.37$ GHz

At 100 *dose we expect 37 GHz for 6mm² at $2E14$

For T= 23 C and 450 nm
(FBK peaks at 410 nm)



For both we expect about 20% PDE at 420 nm and 2V overvoltage



Anti reflective coating also blocks the light < 400 nm

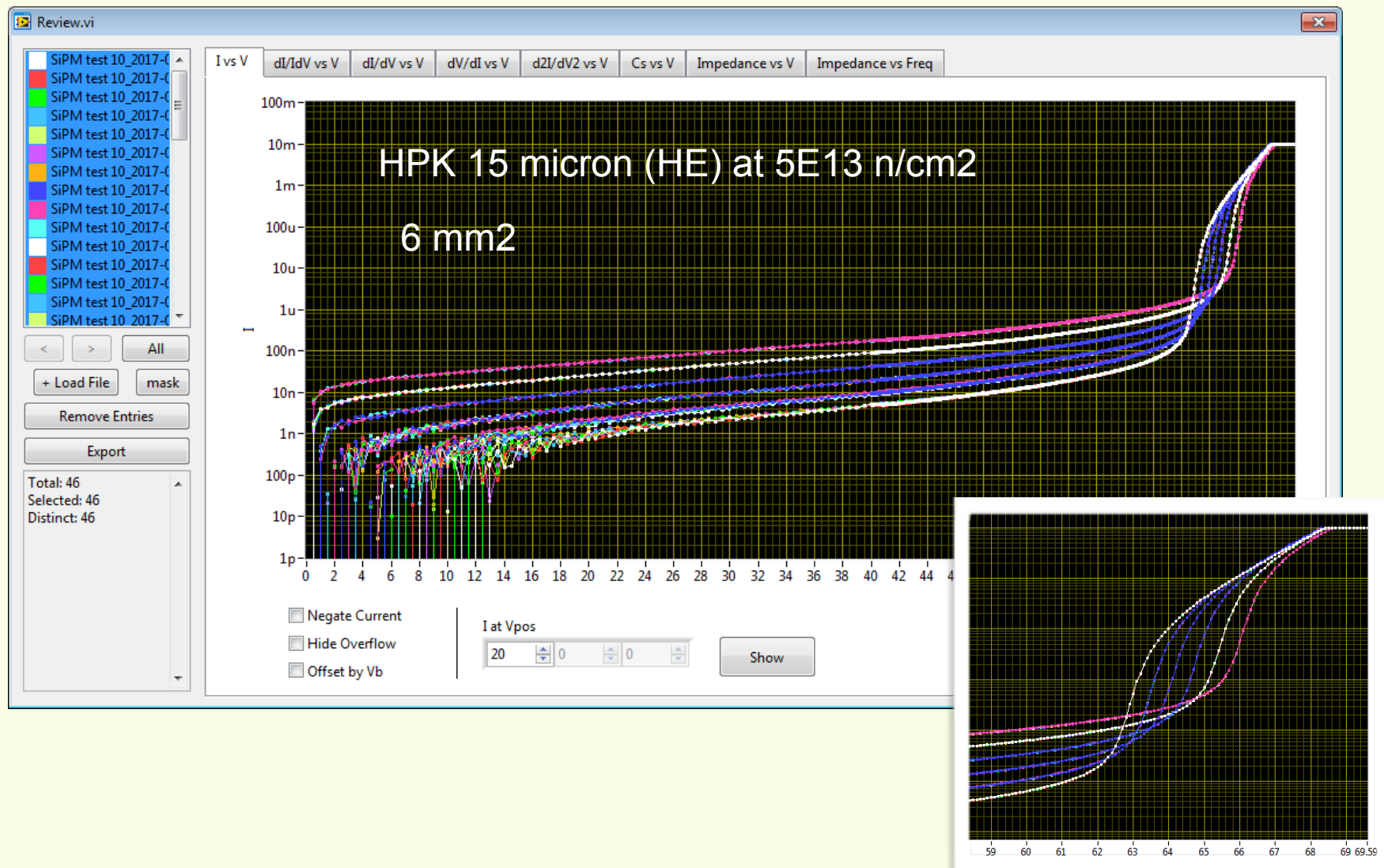
Devices radiated at $5E13$ n/cm² were shipped in cold from JSI to CERN
Then left in the freezer at around -20C for 6 months

Setup and measurements in Lab in CERN Bat28 Climat Chamber (M.Moll)
were done by:

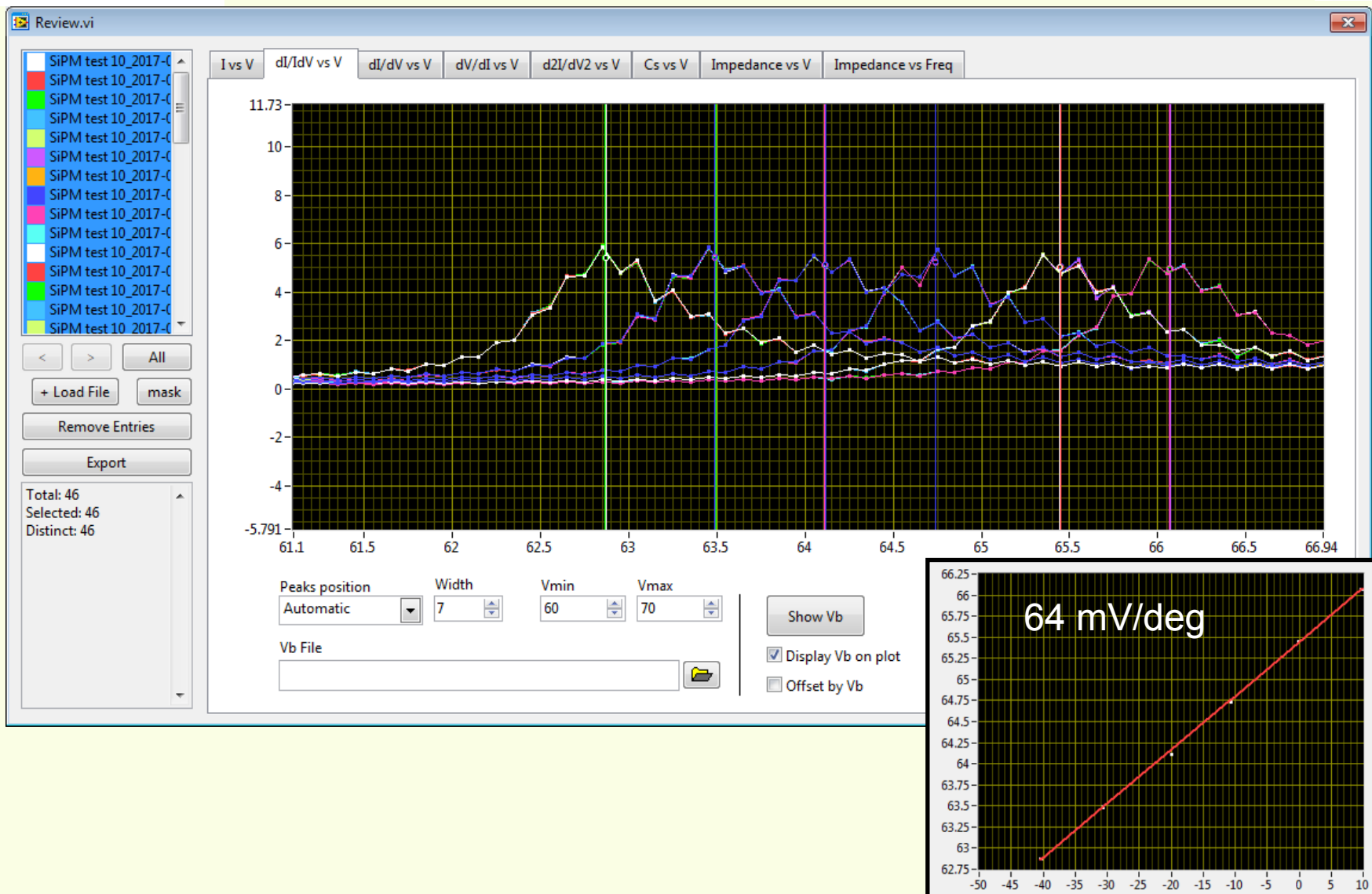
J. Gonzalez

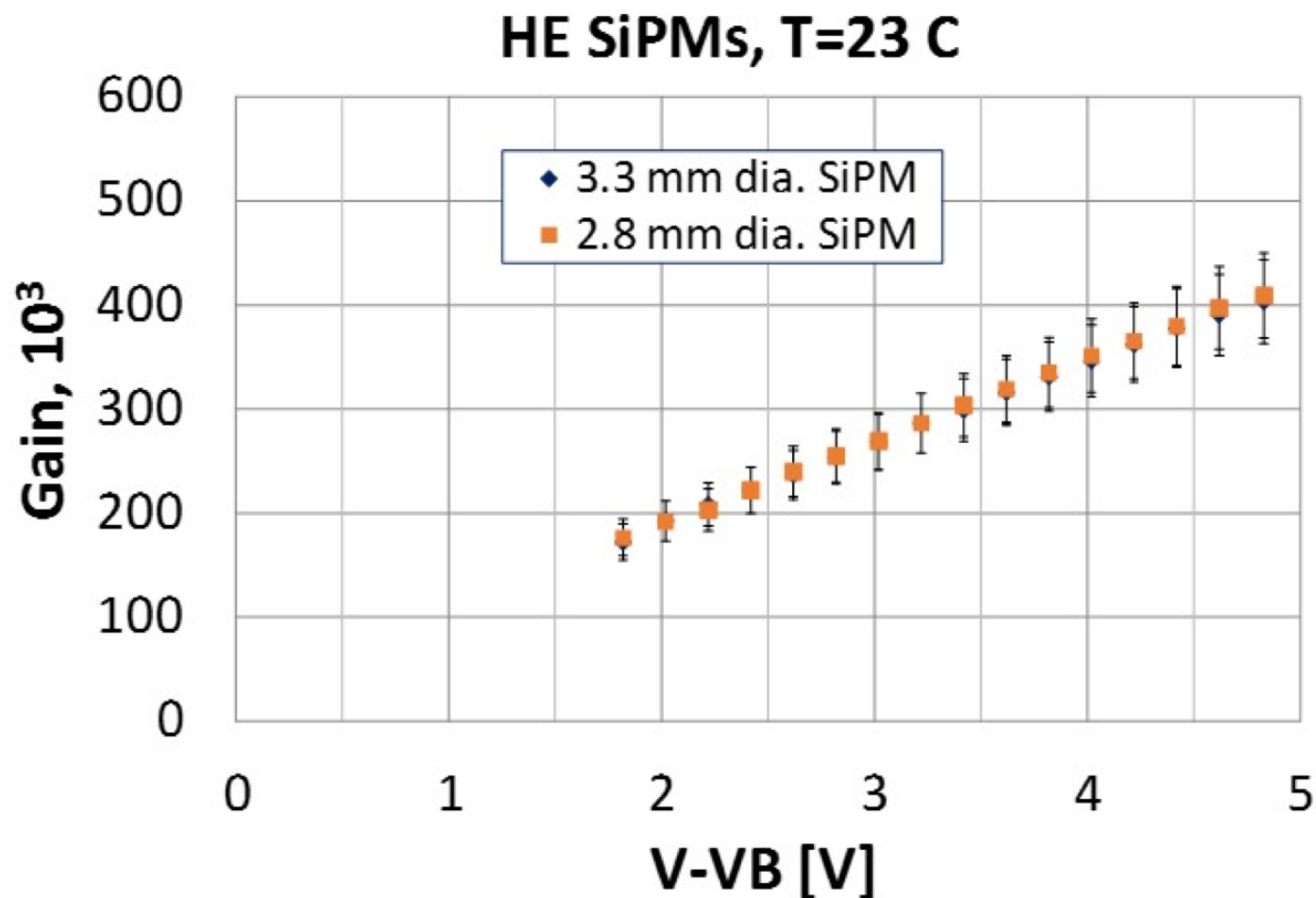
We focus here on the best candidates:
FBK NuV 15 micron low field and HPK 15 micron (HE device)

HPK: IV at T= 10,0,-10,-20,-30 and -40V

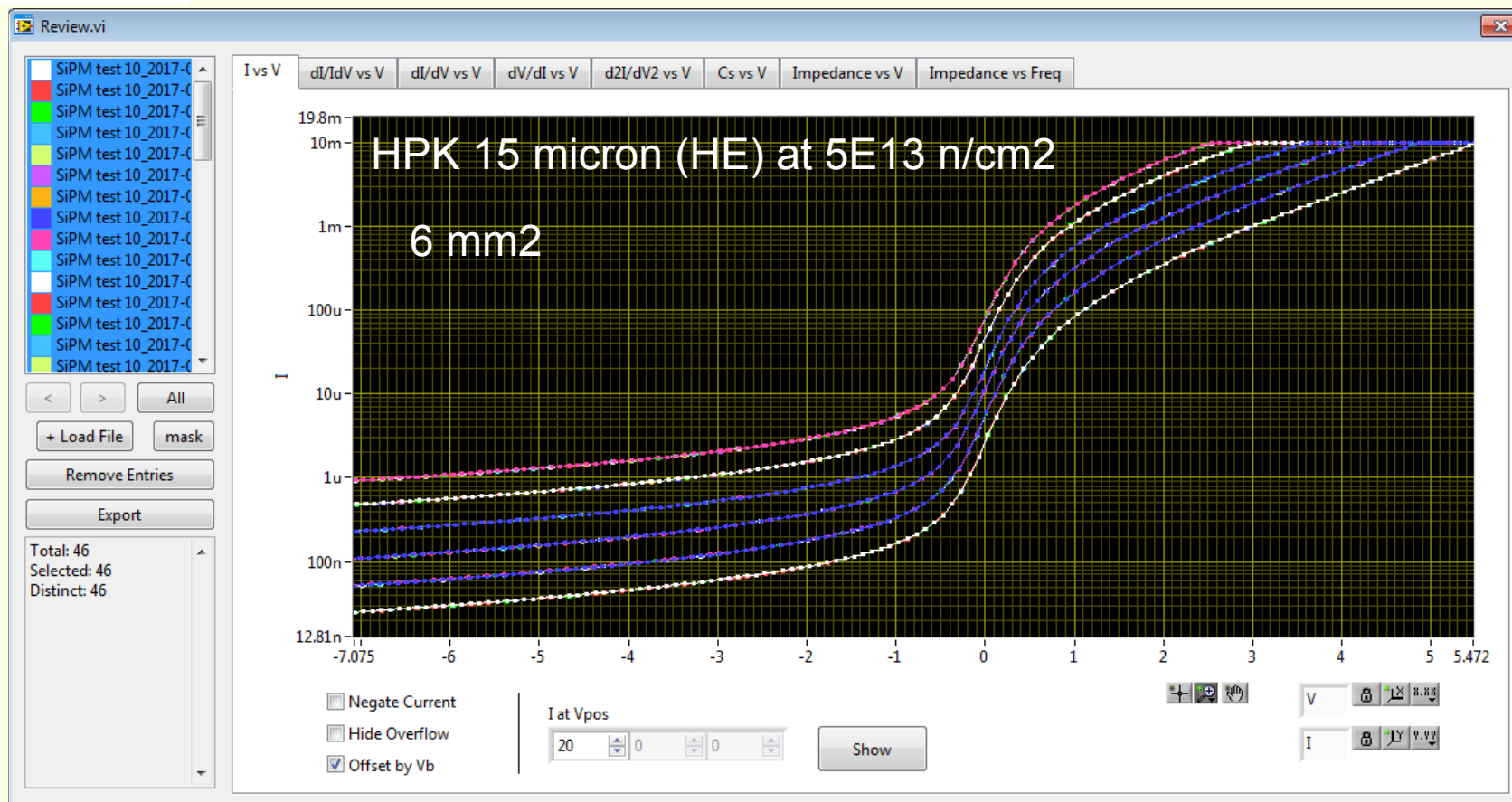


Calculation of Breakdown voltage



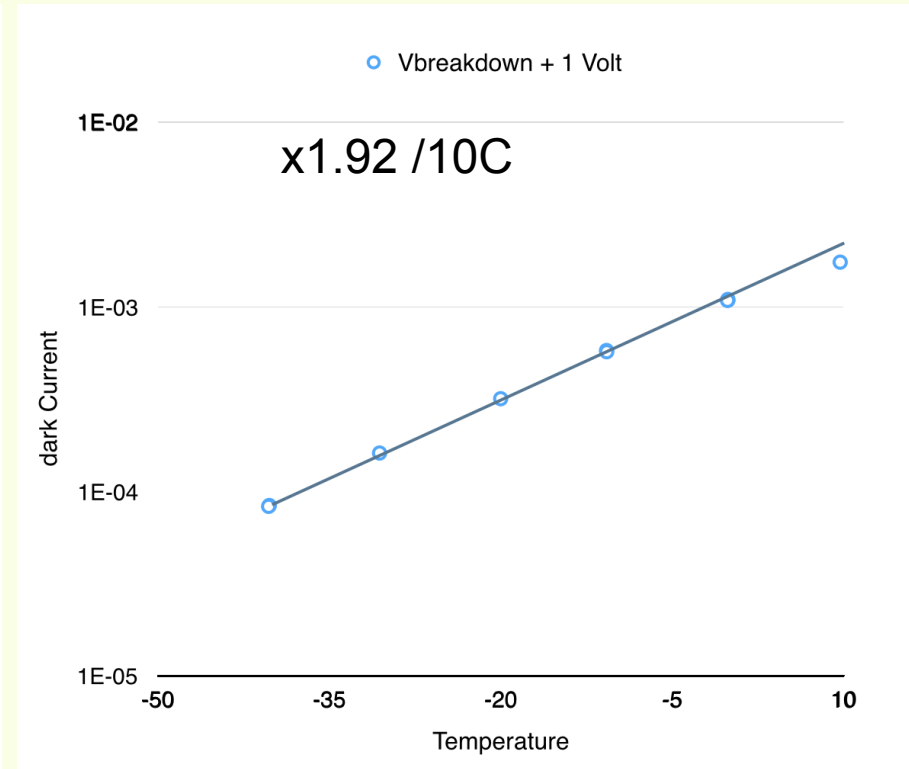
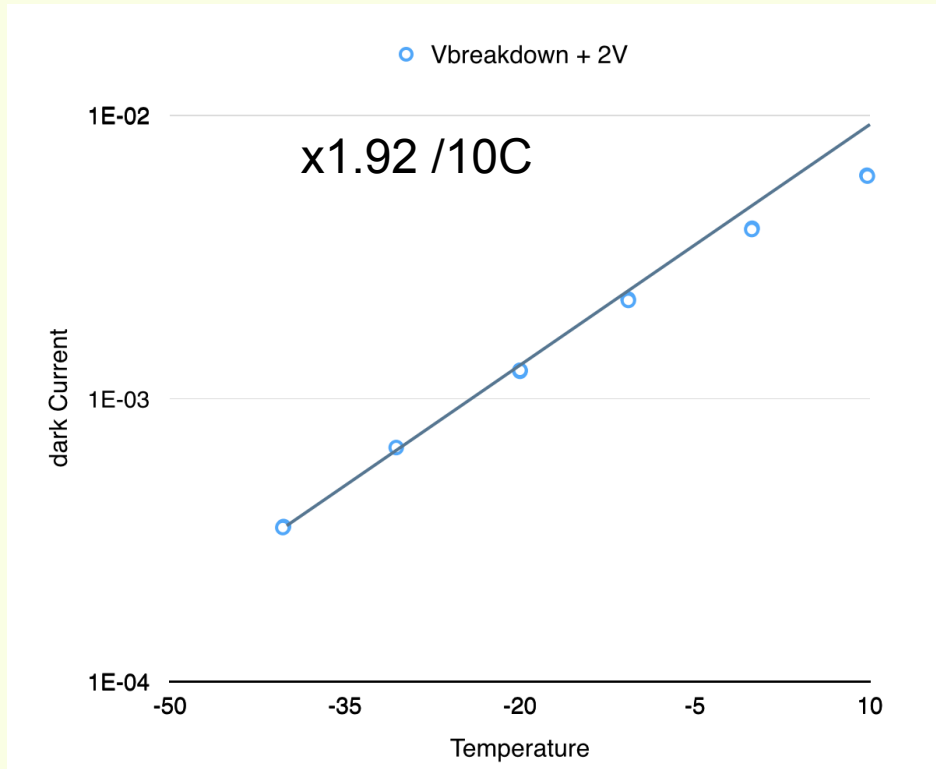


HPK: IV at T= 10,0,-10,-20,-30 and -40V

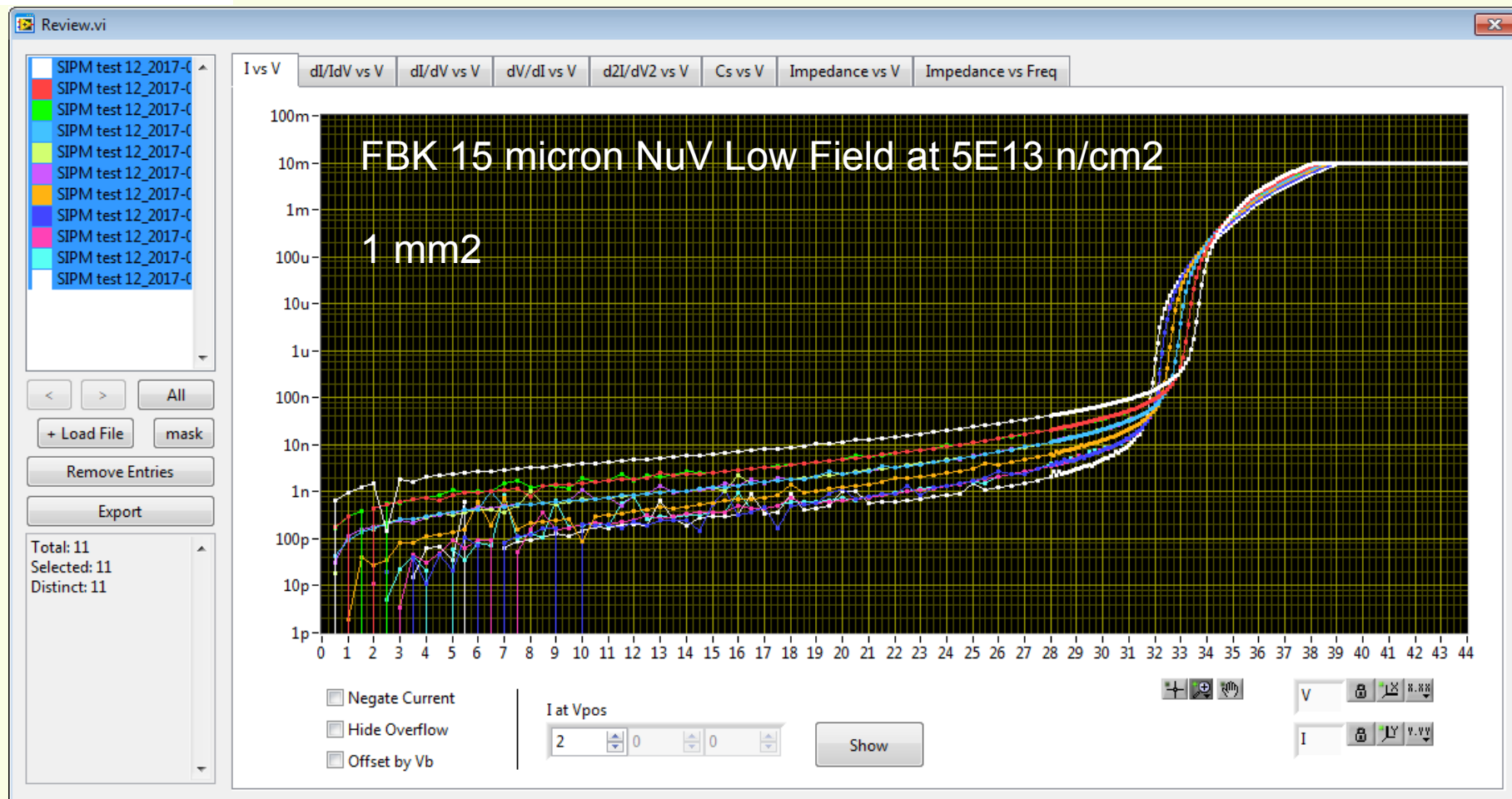


Estimate of the DCR at 2V ($I / \text{Gain} * 1/q$) = 15 GHz at -35C
for 6mm2 (or 2.5 GHz/mm2)

6 mm² HPK 15 micron (HE) at 5E13 n/cm²

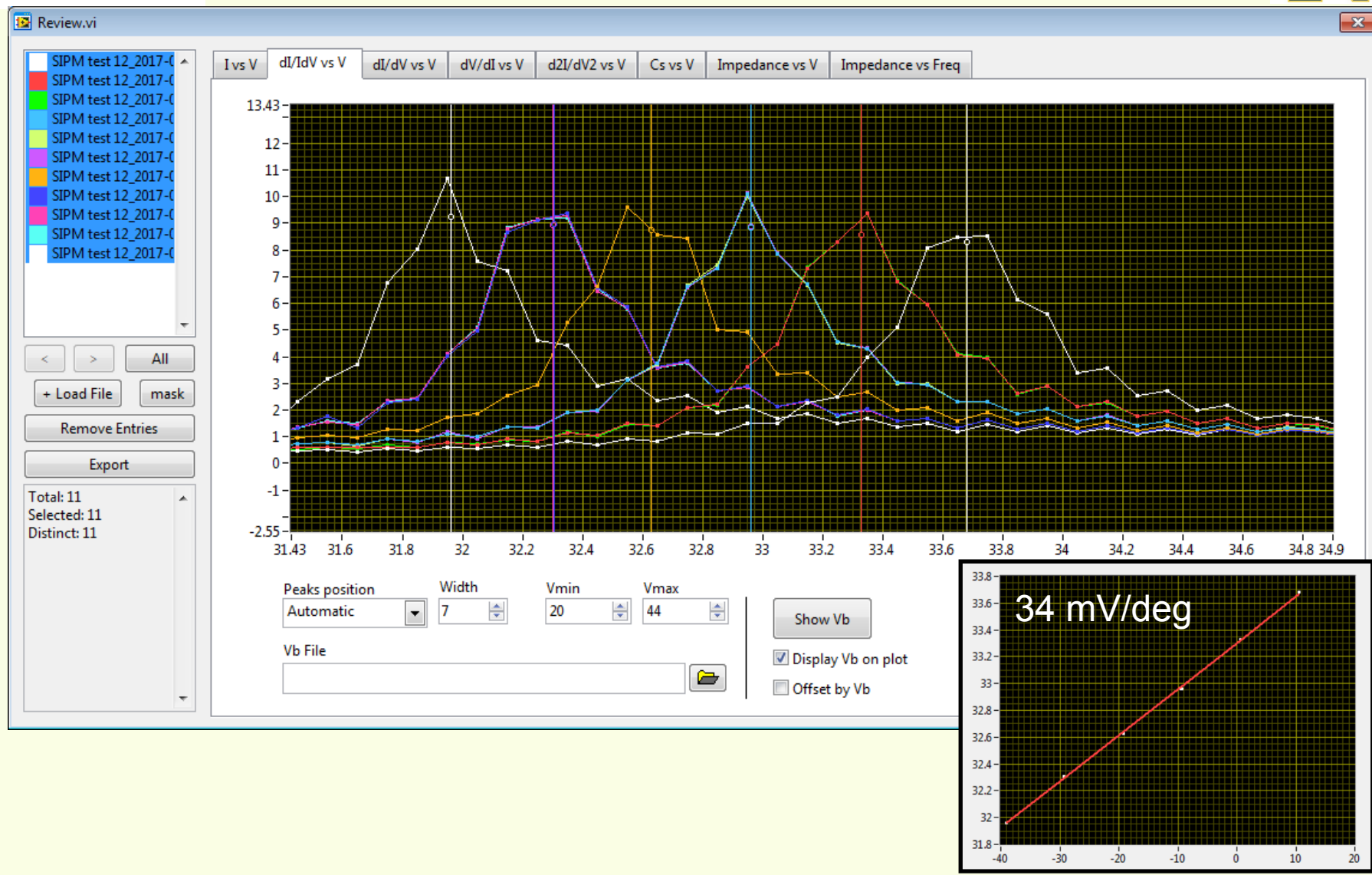


FBK : IV at T= 10,0,-10,-20,-30 and -40V

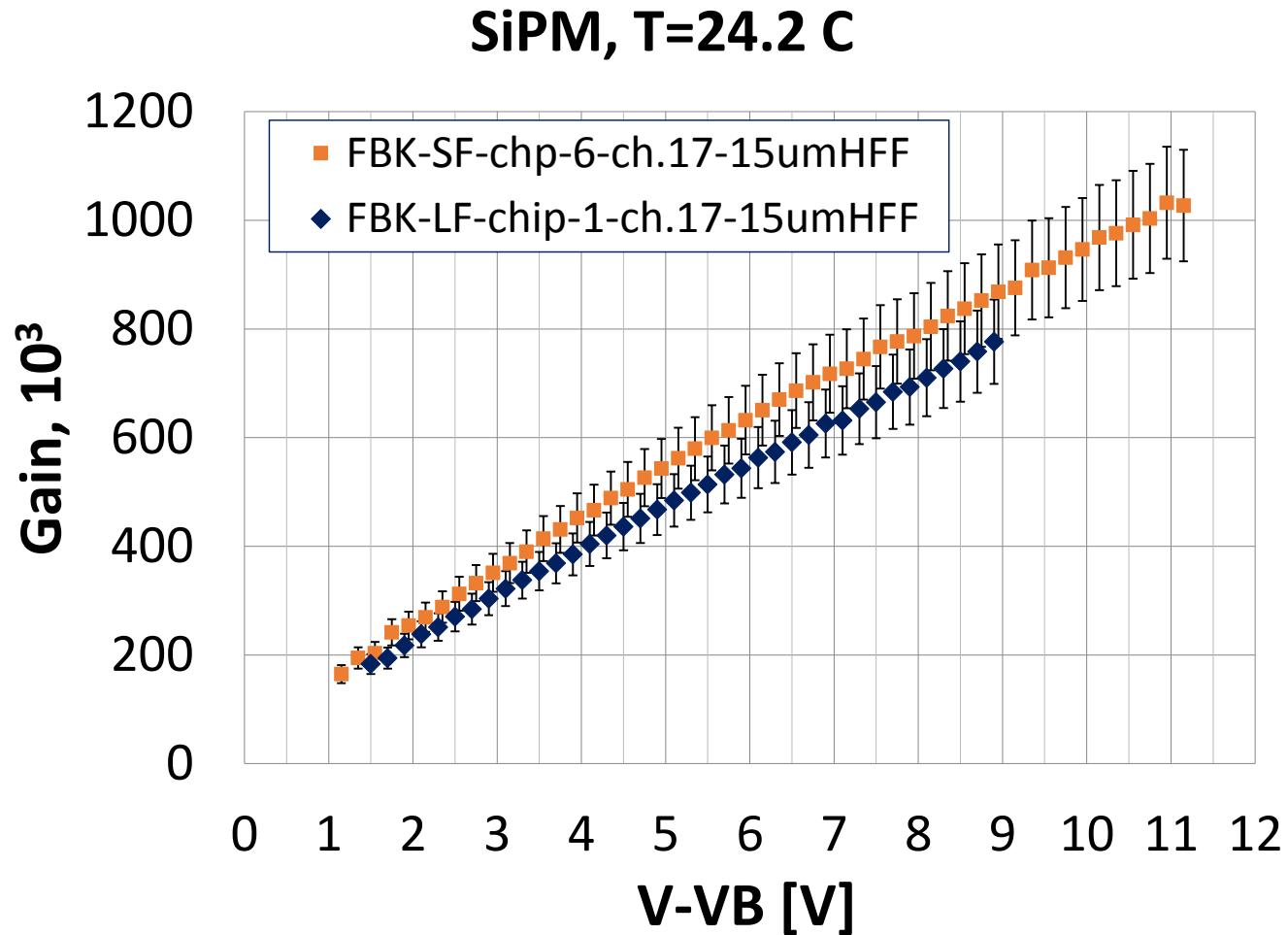


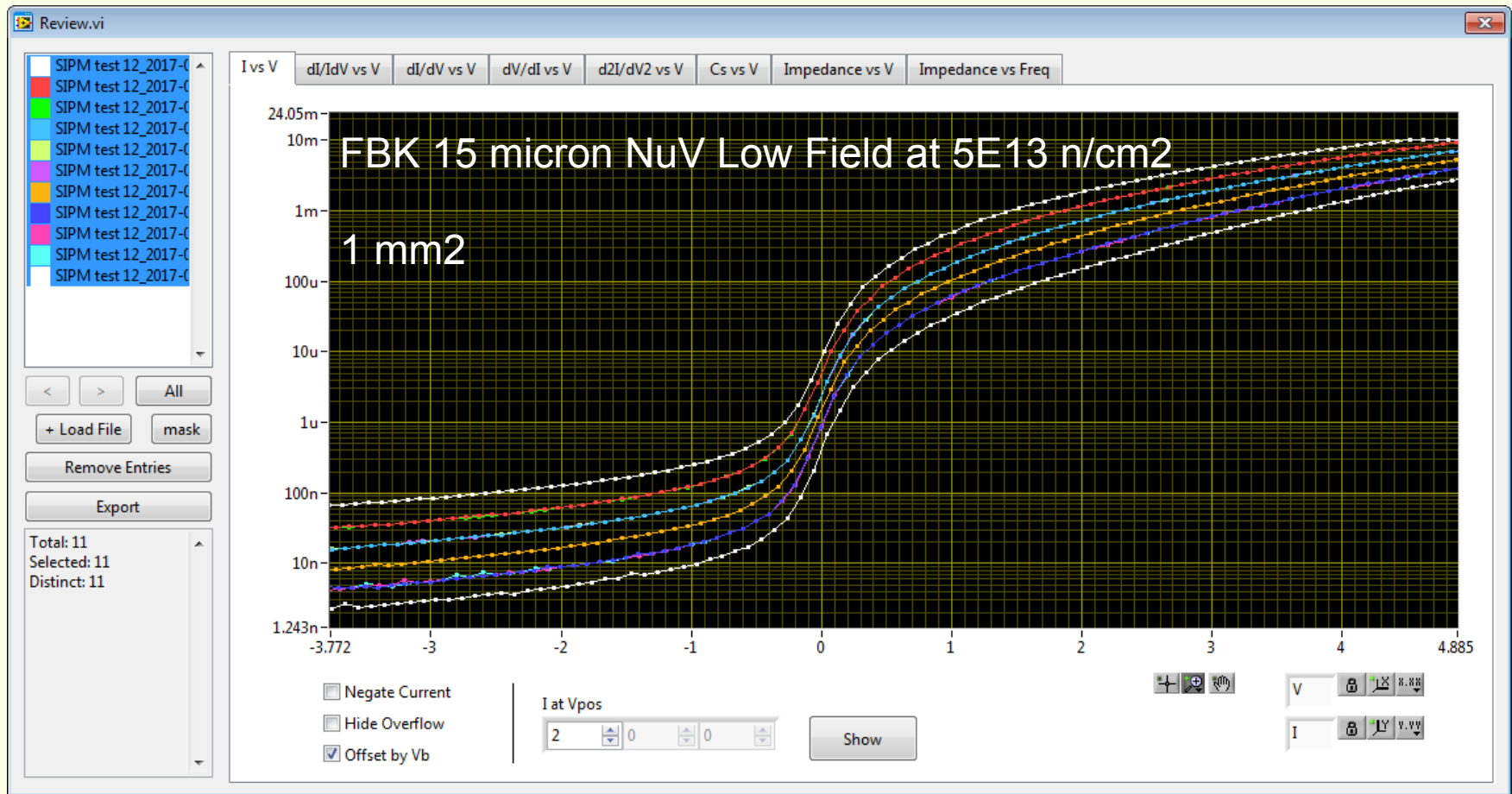
Vb is lower ; around 34V

FBK : IV at T= 10,0,-10,-20,-30 and -40V



FBK NuV gain

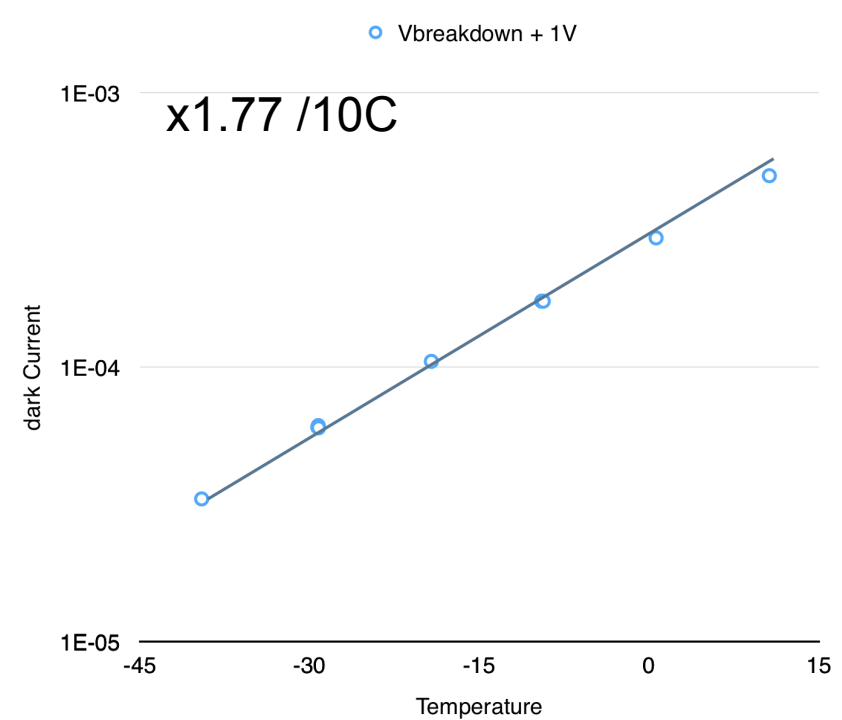
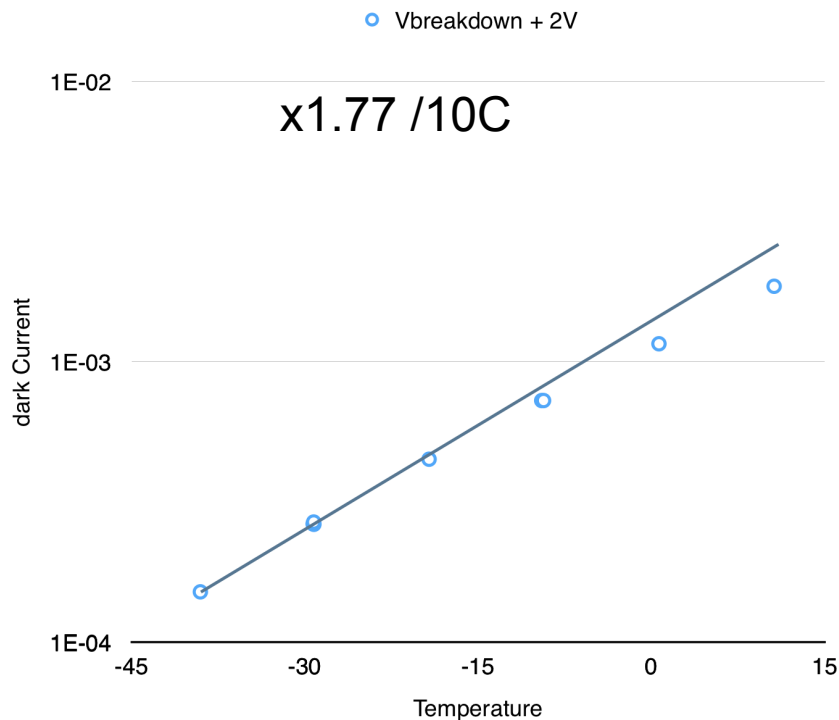




Estimate of the DCR at 2V ($I / \text{Gain} * 1/q$) = 5 GHz at -35C for 1mm2

Dark current vs Temp

1 mm² FBK 15 micron NuV Low Field at 5E13 n/cm²



SF (standard field) has a coefficient of only 1.65

Advantages /Dis- of LF devices

Low Field SiPM advantages:

- Lower current/noise at Low Temperatures
- Lower Capacitance (linear with voltage)
- Lower Gain (power consumption)

Disadvantages:

- higher Voltage (power)
- Cross talk higher (trench technology is harder with thick epo)
- Larger Breakdown voltage shift vs radiation

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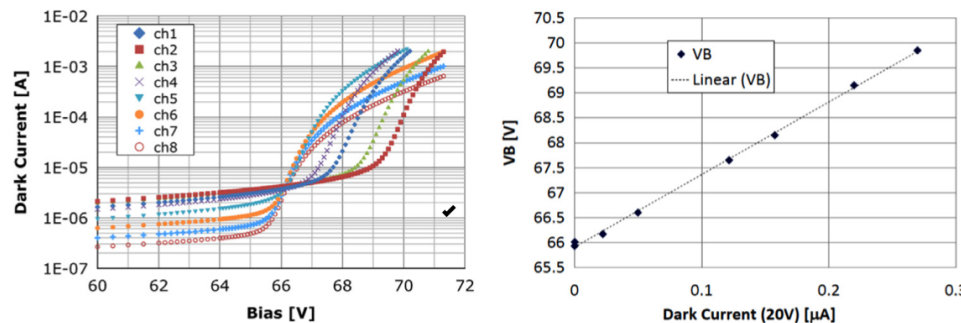
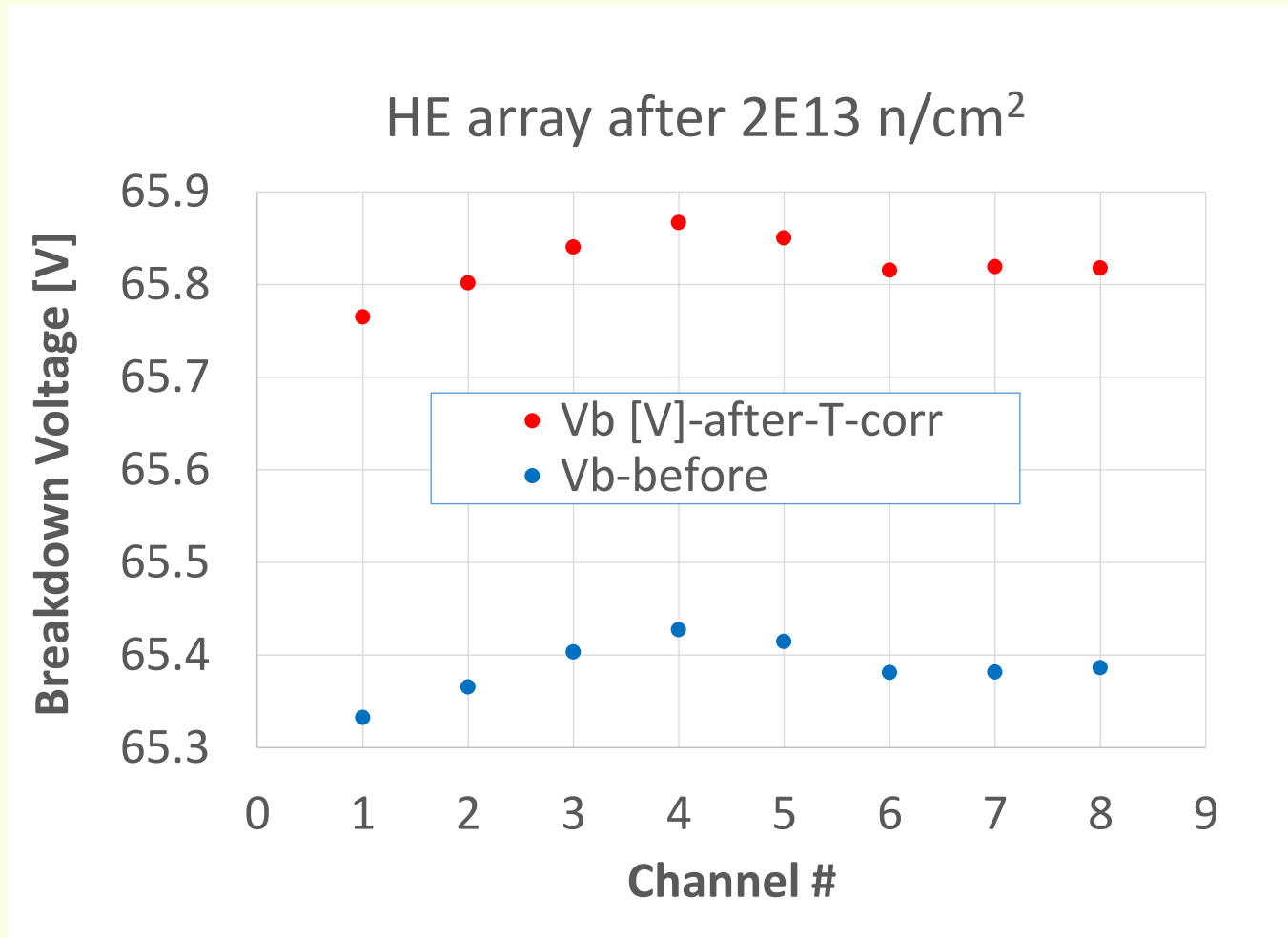


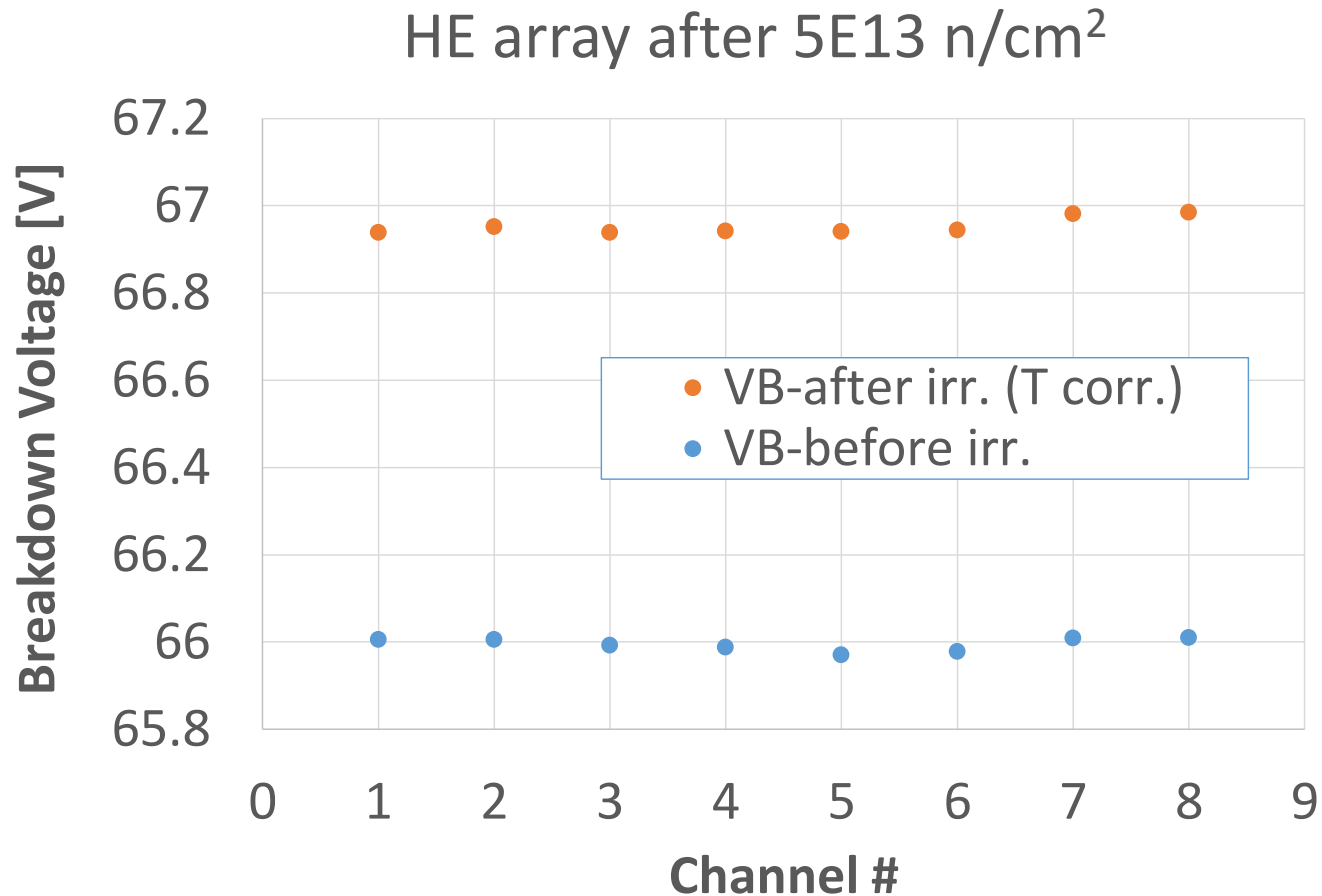
Fig. 3. 10 μm cell HPK 8 channel array with $\varnothing$ 2.8 mm SiPMs with a maximum dose of 2.2×10^{14} n/cm² in channel 2. (a) Dark current vs. bias voltage. (b) Bias voltage shift vs. dark current at gain 1.

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Beam, p







The main issue with SiPMs with very high radiation is the large leakage current and gain.

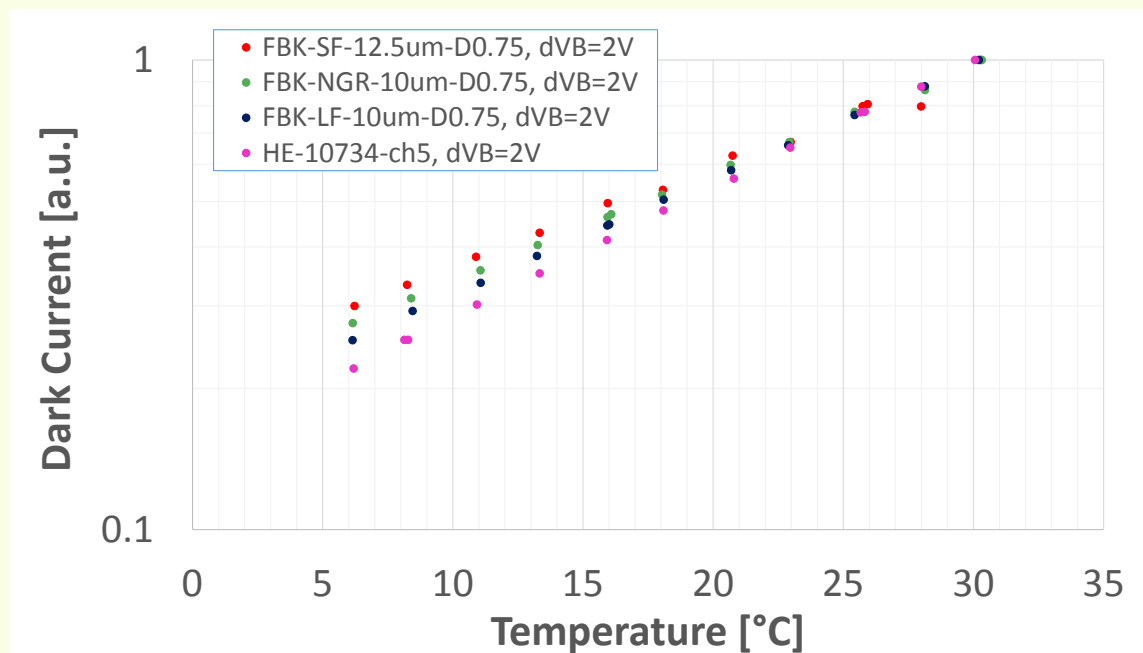
We found that low field SiPMs perform better with radiation specially at low temperature.

We like to continue further on going SiPM R&D focussed on:

- Low Field SiPMs with high Breakdown voltage (60,90,120 V).

We like to thank JSI for the radiation sessions in the last years!
In particular Vladimir Cindro

Dark current (dVB=2 V, norm.) vs T



Vbrd , coefficient (/10C)

SF = 28V , 1.64

NGR = 30V, 1.71

LF = 34V, 1.77

HPK =65V, 1.87

Yuri Musienko:

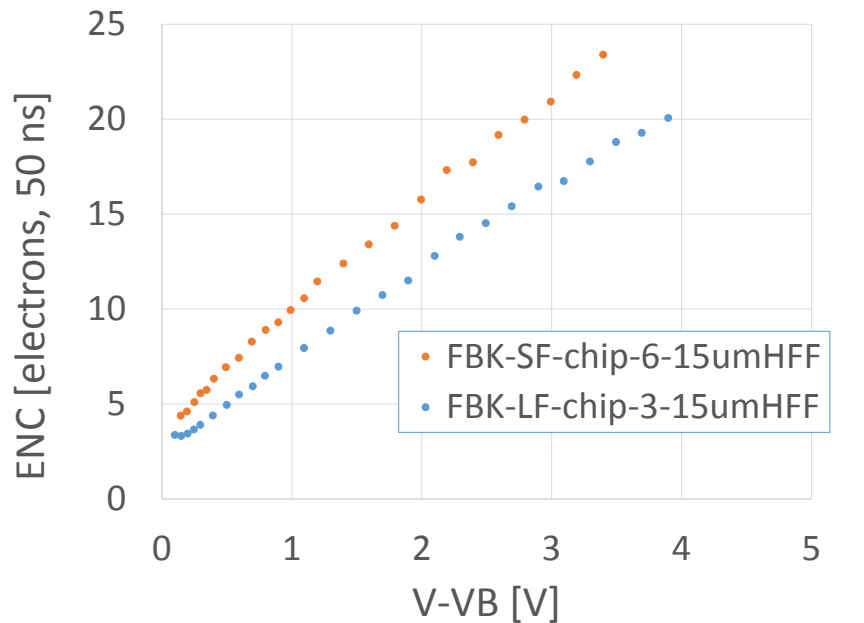
https://indico.cern.ch/event/645439/contributions/2623381/attachments/1478553/2291622/FBK_UHD-3_SiPMs-after-2E12n-v4.pdf

NUV FBK (after annealing)

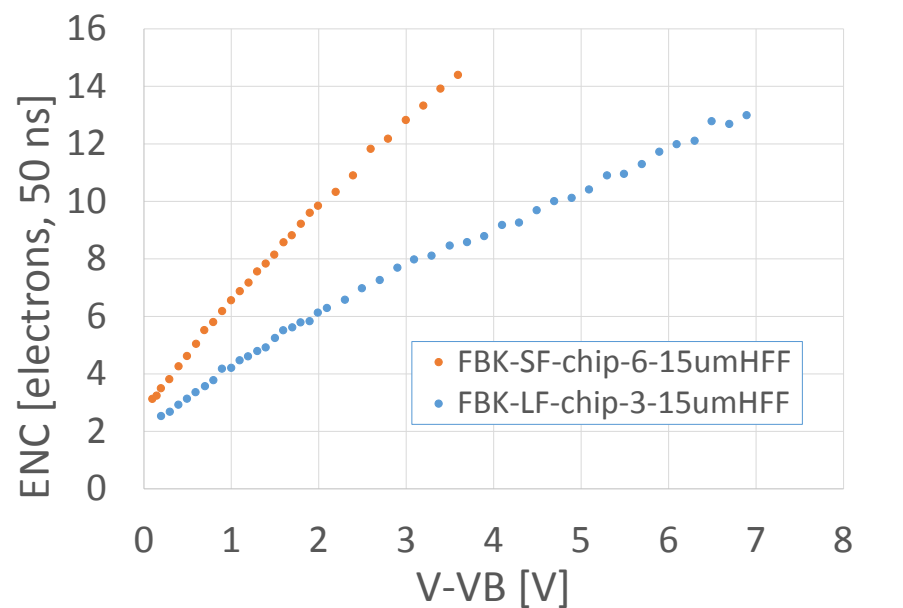
After $2E12$ n/cm² , Area is 1 mm²

T= 23C

T= -24C



ENC(SF)/ENC(LF) $\sim$ 1.27 at dVB=3V



ENC(SF)/ENC(LF) = 1.63 at dVB=3V (ratio=1.27 at room T)